MOSFET – Small Signal, Complementary with ESD Protection, SOT-563

20 V, 540 mA / -430 mA

Features

- Leading Trench Technology for Low RDS(on) Performance
- High Efficiency System Performance
- Low Threshold Voltage
- ESD Protected Gate
- Small Footprint 1.6 x 1.6 mm
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- DC-DC Conversion Circuits
- Load/Power Switching with Level Shift
- Single or Dual Cell Li-Ion Battery Operated Systems
- High Speed Circuits
- Cell Phones, MP3s, Digital Cameras, and PDAs

MAXIMUM RATINGS (T, I = 25°C unless otherwise specified)

Para	Symbol	Value	Unit			
Drain-to-Source Voltage	V_{DSS}	20	V			
Gate-to-Source Voltag	е		V _{GS}	±6	٧	
N-Channel Continu-	Steady	$T_A = 25^{\circ}C$		540	mA	
ous Drain Current (Note 1)	State	T _A = 85°C		390		
	t ≤ 5 s	$T_A = 25^{\circ}C$		570		
P-Channel Continu-	Steady	T _A = 25°C	ID	-430		
ous Drain Current (Note 1)	State	T _A = 85°C		-310		
	t ≤ 5 s	$T_A = 25^{\circ}C$		-455		
Power Dissipation				250		
(Note 1)	State	$T_A = 25^{\circ}C$	P_{D}		mW	
	t ≤ 5 s			280		
Pulsed Drain Current	N-Channel	t _p = 10 μs	I _{DM}	1500	mA	
	P-Channel	ι _p – 10 μ3	MU	-750	IIIA	
Operating Junction and	T _J ,	-55 to	°C			
	T _{STG}	150				
Source Current (Body [I _S	350	mA			
Lead Temperature for S (1/8" from case for 1	TL	260 L				

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface-mounted on FR4 board using 1 in sq. pad size (Cu area = 1.127 in sq [1 oz] including traces).

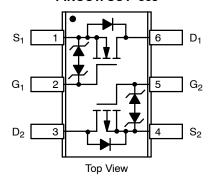


ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(on)} Typ	I _D Max (Note 1)
	0.4 Ω @ 4.5 V	
N-Channel 20 V	0.5 Ω @ 2.5 V	540 mA
20 1	0.7 Ω @ 1.8 V	
	0.5 Ω @ -4.5 V	
P-Channel -20 V	0.6 Ω @ -2.5 V	–430 mA
_ 5 •	1.0 Ω @ -1.8 V	

PINOUT: SOT-563





TW = Specific Device Code

M = Date Code ■ = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]		
NTZD3155CT1G	SOT-563 (Pb-Free)	4000 / Tape & Reel		
NTZD3155CT2G				
NTZD3155CT5G		8000 / Tape & Reel		

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Thermal Resistance Ratings

Parameter	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	500	°C/W
Junction-to-Ambient - t = 5 s (Note 2)		447	

^{2.} Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise specified)

Parameter	Symbol	N/P	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							-	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	N	V _{GS} = 0 V	I _D = 250 μA	20			V
		Р		I _D = -250 μA	-20			
Drain-to-Source Breakdown Voltage Temperature Coefficient	V(_{BR)DSS} /T _J					18		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	N	V _{GS} = 0 V, V _{DS} = 16 V	T _J = 25°C			1.0	μΑ
		Р	$V_{GS} = 0 \text{ V}, V_{DS} = -16 \text{ V}$				-1.0	
		N	V _{GS} = 0 V, V _{DS} = 16 V	T _J = 125°C			2.0	μΑ
		Р	V _{GS} = 0 V, V _{DS} = - 16V	1			-5.0	
Gate-to-Source Leakage Current	I _{GSS}	Р	V _{DS} = 0 V, V _{GS} =	±4.5 V			±2.0	μΑ
		N	1				±5.0	
ON CHARACTERISTICS (Note 3)							-	
Gate Threshold Voltage	V _{GS(TH)}	N	$V_{GS} = V_{DS}$	I _D = 250 μA	0.45		1.0	V
		Р		I _D = -250 μA	-0.45		-1.0	
Gate Threshold Temperature Coefficient	V _{GS(TH)} /T _J					-1.9		-mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	N	V_{GS} = 4.5 V, I_{D} = 540 mA V_{GS} = -4.5 V, I_{D} = -430 mA V_{GS} = 2.5 V, I_{D} = 500 mA			0.4	0.55	
		Р				0.5	0.9	
		N				0.5	0.7	
		P $V_{GS} = -2.5V$, $I_D = -300 \text{ mA}$			0.6	1.2	Ω	
		N	V _{GS} = 1.8 V, I _D = 350 mA			0.7	0.9	
		Р	$V_{GS} = -1.8V$, $I_D = -150$ mA			1.0	2.0	
Forward Transconductance	9 _{FS}	N	V _{DS} = 10 V, I _D = 5	540 mA		1.0		
		Р	V _{DS} = -10 V, I _D = -	-430 mA		1.0		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE						
Input Capacitance	C _{ISS}					80	150	
Output Capacitance	C _{OSS}	N	N $f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$ $V_{DS} = 16 \text{ V}$			13	25	1
Reverse Transfer Capacitance	C _{RSS}	1				10	20	. –
Input Capacitance	C _{ISS}					105	175	pF
Output Capacitance	C _{OSS}	Р	f = 1 MHz, V _{GS} = 0 V V _{DS} = -16 V			15	30	1
Reverse Transfer Capacitance	C _{RSS}	1	↑D2 = 10	•		10	20	

^{3.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	N/P	Test Condition		Min	Тур	Max	Unit	
CHARGES, CAPACITANCES AND GATE RESISTANCE									
Total Gate Charge	Q _{G(TOT)}					1.5	2.5		
Threshold Gate Charge	Q _{G(TH)}	N	V 45VV 40V			0.1			
Gate-to-Source Charge	Q _{GS}	1	$V_{GS} = 4.5 \text{ V}, V_{DS} = -10 \text{ V}; I_D = 540 \text{ mA}$			0.2			
Gate-to-Drain Charge	Q_{GD}	1				0.35		. 0	
Total Gate Charge	Q _{G(TOT)}					1.7	2.5	nC	
Threshold Gate Charge	Q _{G(TH)}	P	V _{GS} = -4.5 V, V _{DS} = 10 V;	I _D = –380 mA		0.1			
Gate-to-Source Charge	Q _{GS}	1 1				0.3			
Gate-to-Drain Charge	Q_{GD}	1				0.4			
SWITCHING CHARACTERISTIC	CS (V _{GS} = V) (Not	e 4)				•			
Turn-On Delay Time	t _{d(ON)}	N	N $V_{GS} = 4.5 \text{ V}, V_{DD} = -10 \text{ V}, I_D = 540 \text{ mA}, \\ R_G = 10 \ \Omega$			6.0			
Rise Time	t _r					4.0			
Turn-Off Delay Time	t _{d(OFF)}					16			
Fall Time	t _f					8.0			
Turn-On Delay Time	t _{d(ON)}	Р				10		ns	
Rise Time	t _r		V _{GS} = -4.5 V, V _{DD} = 10 V, I	n = -215 mA.		12			
Turn-Off Delay Time	t _{d(OFF)}	1	$R_G = 10 \Omega$			35			
Fall Time	t _f	1				19			
Drain-Source Diode Character	Drain-Source Diode Characteristics								
Forward Diode Voltage	V_{SD}	N	$V_{GS} = 0 \text{ V}, T_J = 25^{\circ}\text{C}$ $I_S = 350 \text{ mA}$ $I_S = -350 \text{ mA}$			0.7	1.2	.,	
		Р				-0.8	-1.2	V	
Reverse Recovery Time	t _{RR}	N	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$			6.5			
		Р				13		ns	

^{4.} Switching characteristics are independent of operating junction temperatures

N-CHANNEL TYPICAL PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)

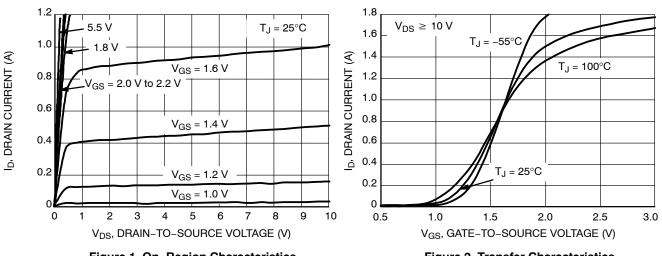


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

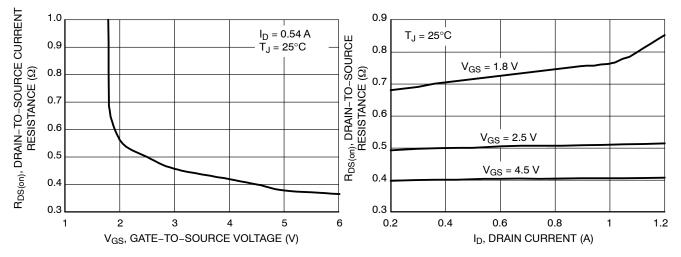


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Gate Voltage

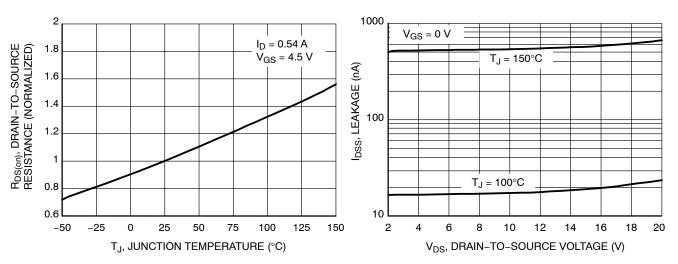


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage

N-CHANNEL TYPICAL PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)

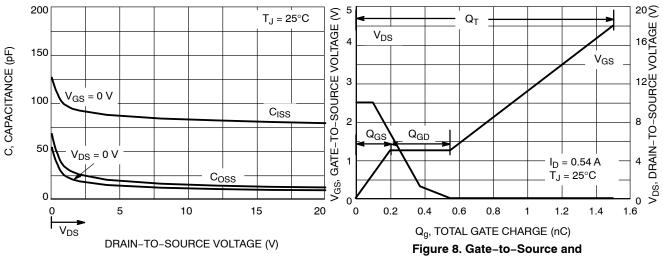


Figure 7. Capacitance Variation

Drain-to-Source Voltage versus Total Charge

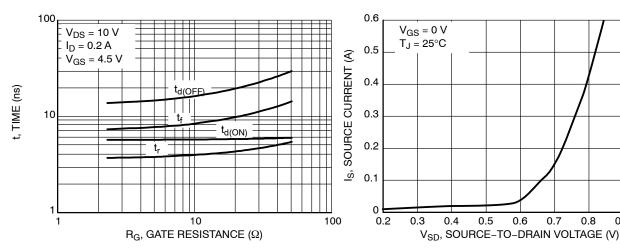


Figure 9. Resistive Switching Time Variation versus Gate Resistance

Figure 10. Diode Forward Voltage versus Current

P-CHANNEL TYPICAL PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)

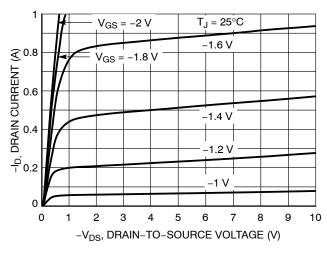


Figure 1. On-Region Characteristics

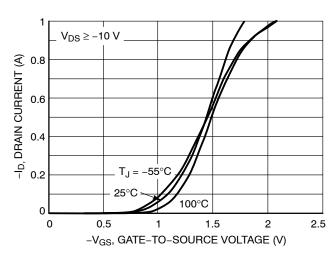


Figure 2. Transfer Characteristics

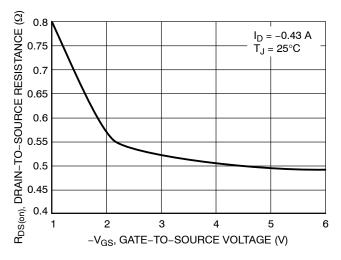


Figure 3. On-Resistance vs. Gate-to-Source Voltage

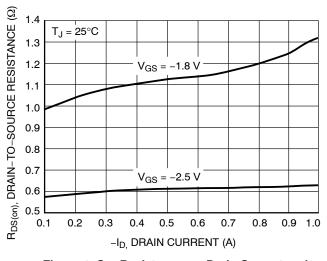


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

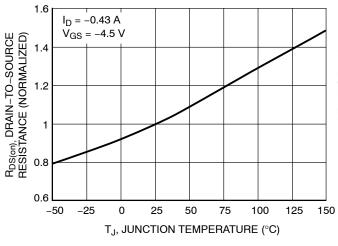


Figure 5. On–Resistance Variation with Temperature

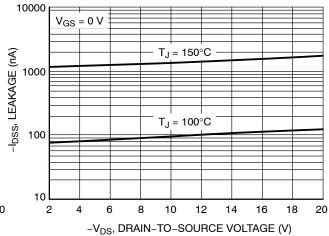


Figure 6. Drain-to-Source Leakage Current vs. Voltage

P-CHANNEL TYPICAL PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)

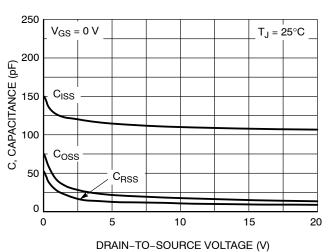
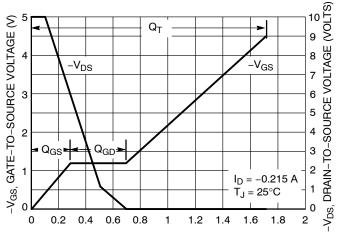


Figure 7. Capacitance Variation



Q_G, TOTAL GATE CHARGE (nC)

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

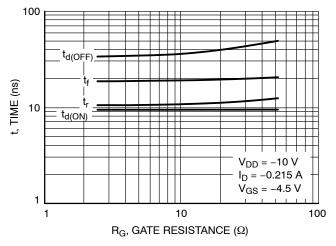


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

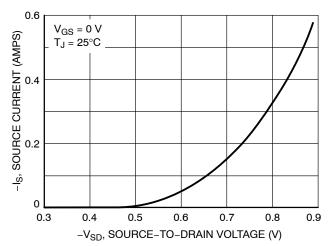
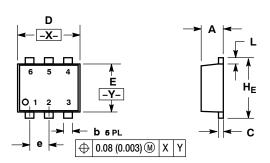


Figure 10. Diode Forward Voltage vs. Current

PACKAGE DIMENSIONS

SOT-563, 6 LEAD CASE 463A ISSUE F

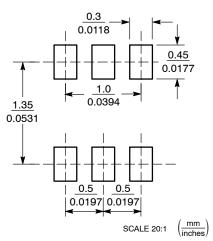


NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.50	0.55	0.60	0.020	0.021	0.023	
b	0.17	0.22	0.27	0.007	0.009	0.011	
С	0.08	0.12	0.18	0.003	0.005	0.007	
D	1.50	1.60	1.70	0.059	0.062	0.066	
Е	1.10	1.20	1.30	0.043	0.047	0.051	
е		0.5 BSC		0.02 BSC			
L	0.10	0.20	0.30	0.004	0.008	0.012	
HE	1.50	1.60	1.70	0.059	0.062	0.066	

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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